

ABSTRACT OF THE DISCLOSURE

For simulation of an electric characteristic of a circuit including transistors, a plurality of transistors are arranged in a matrix pattern on the basis of sizes of the transistors, and data of the electric characteristic measured on first transistors among the plurality of transistors are stored in the matrix pattern. When a position of a second transistor different from the first transistors is specified in the matrix pattern, data of the electric characteristic of the second transistor are determined according to interpolation rules by using the measured data of the one or more first transistors if there are one or more first transistors in the plurality of first transistor at one or more positions adjacent to the position of the second transistor in the matrix pattern.